



Application/Control	No. Applicant(s)/Patent Reexamination	under
10/684,909	MOLL ET AL.	
Examiner	Art Unit	
Tanh Q. Nguyen	2182	

SEARCHED					
Class	Subclass	Date	Examiner		
709	201, 702 205,213-215 217, 218,222 221,248,242	01/04/06	TON		
	221,248,246				
710	15,11-4				
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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